

Subclass	ISSUE CLASSIFICATION
Class	

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PATENT NUMBER

# U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

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SCANNED

APPLICATION NO. 09/856982	CONT/PRIOR D F	CLASS 356	SUBCLASS 237.4	ART UNIT 2877 <del>2879</del>	EXAMINER Nguyen Si
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2877

TITLE

Method for inspecting a film of semiconductor wafer

PTO-2040  
12/99

## ISSUING OFFICE INFORMATION

TERMINAL DISCLAIMER	DRAWINGS			OTHER INFORMATION	
	Sheets Drawn	Figs. Drawn	Print Figs.	Total Claims	Total Figs. in D.G.
<input checked="" type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.  <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____  <input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Assistant Examiner) (Date)  _____ (Primary Examiner) (Date)  _____ (Legal Instruments Examiner) (Date)			NOTICE OF ALLOWANCE MAILED  _____	
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